Noninverting 3−State Buffer

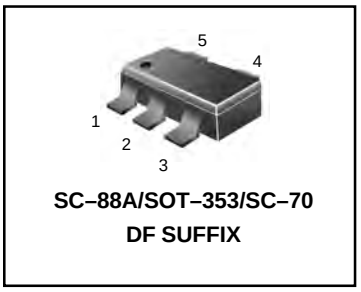
The FC74VHC1G125 is an advanced high speed CMOS noninverting 3 state buffer fabricated with silicon gate noninverting 3 state buffer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The internal circuit is composed of three stages, including a buffered 3-state output which provides high noise immunity and stable output.

The FC74VHC1G125 input structure provides protection when voltages up to 7.0V are applied,regardless of the supply voltage. This allows the FC74VHC1G125 to be used to interface 5.0V circuits to 3.0V circuits.

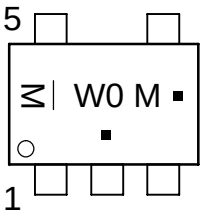
Features

- High Speed: t_{PD} = 3.5 ns (Typ) at V_{CC} = 5.0 V
- Low Power Dissipation: I_{CC} = 1 μA (Max) at T_A = 25℃
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Pin and Function Compatible with Other Standard Logic Families
- Chip Complexity: FETs = 58; Equivalent Gates = 15
- Pb−Free Packages are Available



SC−88A/SOT−353/SC−70
DF SUFFIX

MARKING DIAGRAMS



PIN ASSIGNMENT	
1	$\overline{OE}$
2	IN A
3	GND
4	OUT Y
5	V_{CC}

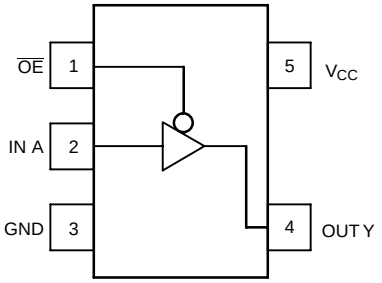


Figure 1. Pinout (Top View)

FUNCTION TABLE

A Input	$\overline{OE}$ Input	Y Output
L	L	L
H	L	H
X	H	Z

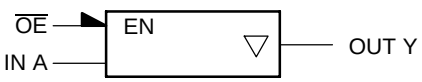


Figure 2. Logic Symbol

MAXIMUM RATINGS

Symbol	Characteristics		Value	Unit
V_{CC}	DC Supply Voltage		−0.5 to +7.0	V
V_{IN}	DC Input Voltage		−0.5 to +7.0	V
V_{OUT}	DC Output Voltage	V_{CC} = 0 High or Low State	−0.5 to 7.0 −0.5 to V_{CC} + 0.5	V
I_{IK}	Input Diode Current		−20	mA
I_{OK}	Output Diode Current	V_{OUT} < GND; V_{OUT} > V_{CC}	+20	mA
I_{OUT}	DC Output Current, per Pin		+25	mA
I_{CC}	DC Supply Current, V_{CC} and GND		+50	mA
P_D	Power Dissipation in Still Air		200	mW
θ_{JA}	Thermal Resistance		333	°C/W
T_L	Lead Temperature, 1 mm from Case for 10 s		260	°C
T_J	Junction Temperature Under Bias		+150	°C
T_{stg}	Storage Temperature		−65 to +150	°C
V_{ESD}	ESD Withstand Voltage	Human Body Model (Note 1) Machine Model (Note 2) Charged Device Model (Note 3)	> 2000 > 200 N/A	V
$I_{Latchup}$	Latchup Performance	Above V_{CC} and Below GND at 125°C (Note 4)	±500	mA

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. Tested to EIA/JESD22−A114−A.
2. Tested to EIA/JESD22−A115−A.
3. Tested to JESD22−C101−A.
4. Tested to EIA/JESD78.

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics		Min	Max	Unit
V_{CC}	DC Supply Voltage		2.0	5.5	V
V_{IN}	DC Input Voltage		0.0	5.5	V
V_{OUT}	DC Output Voltage		0.0	V_{CC}	V
T_A	Operating Temperature Range		−55	+125	°C
t_r , t_f	Input Rise and Fall Time	V_{CC} = 3.3 V ± 0.3 V V_{CC} = 5.0 V ± 0.5 V	0 0	100 20	ns/V

Device Junction Temperature versus Time to 0.1% Bond Failures

Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

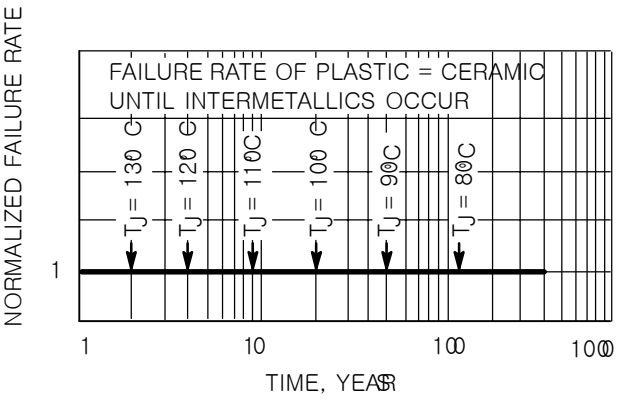


Figure 3. Failure Rate vs. Time Junction Temperature

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	V_{CC} (V)	T_A = 25°C			$T_A \leq 85°C$		$-55 \leq T_A \leq 125°C$		Unit
				Min	Typ	Max	Min	Max	Min	Max	
V_{IH}	Minimum High−Level Input Voltage		2.0 3.0 4.5 5.5	1.5 2.1 3.15 3.85			1.5 2.1 3.15 3.85		1.5 2.1 3.15 3.85		V
V_{IL}	Maximum Low−Level Input Voltage		2.0 3.0 4.5 5.5			0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65	V
V_{OH}	Minimum High−Level Output Voltage $V_{IN} = V_{IH}$ or V_{IL}	$V_{IN} = V_{IH}$ or V_{IL} $I_{OH} = -50$ μA	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5		1.9 2.9 4.4		1.9 2.9 4.4		V
		$V_{IN} = V_{IH}$ or V_{IL} $I_{OH} = -4$ mA $I_{OH} = -8$ mA	3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66		V
V_{OL}	Maximum Low−Level Output Voltage $V_{IN} = V_{IH}$ or V_{IL}	$V_{IN} = V_{IH}$ or V_{IL} $I_{OL} = 50$ μA	2.0 3.0 4.5		0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1		0.1 0.1 0.1	V
		$V_{IN} = V_{IH}$ or V_{IL} $I_{OL} = 4$ mA $I_{OL} = 8$ mA	3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52	V
I_{OZ}	Maximum 3−State Leakage Current	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = V_{CC}$ or GND	5.5			±0.25		±2.5		±2.5	μA
I_{IN}	Maximum Input Leakage Current	V_{IN} = 5.5 V or GND	0 to 5.5			±0.1		±1.0		±1.0	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			1.0		20		40	μA

AC ELECTRICAL CHARACTERISTICS C_{load} = 50 pF, Input $t_r = t_f$ = 3.0 ns

Symbol	Parameter	Test Conditions	T_A = 25°C			$T_A \leq 85°C$		$-55 \leq T_A \leq 125°C$		Unit
			Min	Typ	Max	Min	Max	Min	Max	
t_{PLH}, t_{PHL}	Maximum Propagation Delay, Input A to Y (Figures 3 and 4)	V_{CC} = 3.3 ±0.3 V C_L = 15 pF C_L = 50 pF		4.5 6.4	8.0 11.5		9.5 13.0		12.0 16.0	ns
		V_{CC} = 5.0 ±0.5 V C_L = 15 pF C_L = 50 pF		3.5 4.5	5.5 7.5		6.5 8.5		8.5 10.5	
t_{PZL}, t_{PZH}	Maximum Output Enable Time, Input $\overline{OE}$ to Y (Figures 4 and 5)	V_{CC} = 3.3 ±0.3 V C_L = 15 pF R_L = 1000 Ω C_L = 50 pF		4.5 6.4	8.0 11.5		9.5 13.0		11.5 15.0	ns
		V_{CC} = 5.0 ±0.5 V C_L = 15 pF R_L = 1000 Ω C_L = 50 pF		3.5 4.5	5.1 7.1		6.0 8.0		8.5 10.5	
t_{PLZ}, t_{PHZ}	Maximum Output Disable Time, Input $\overline{OE}$ to Y (Figures 4 and 5)	V_{CC} = 3.3 ±0.3 V C_L = 15 pF R_L 1000 Ω C_L = 50 pF		6.5 8.0	9.7 13.2		11.5 15.0		14.5 18.0	ns
		V_{CC} = 5.0 ±0.5 V C_L = 15 pF R_L = 1000 Ω C_L = 50 pF		4.8 7.0	6.8 8.8		8.0 10.0		10.0 12.0	
C_{IN}	Maximum Input Capacitance			4.0	10		10		10	pF
C_{OUT}	Maximum 3−State Output Capacitance (Output in High Impedance State)			6.0						pF

		Typical @ 25°C, V_{CC} = 5.0 V	
C_{PD}	Power Dissipation Capacitance (Note 5)	8.0	pF

5. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}$. C_{PD} is used to determine the no−load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC2} \bullet f_{in} + I_{CC} \bullet V_{CC}$.

SWITCHING WAVEFORMS

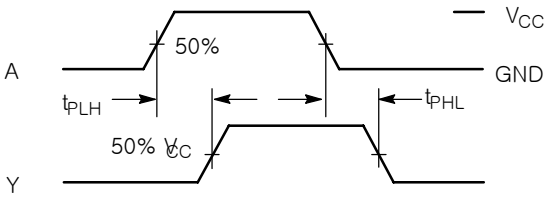


Figure 4. Switching Wave Forms

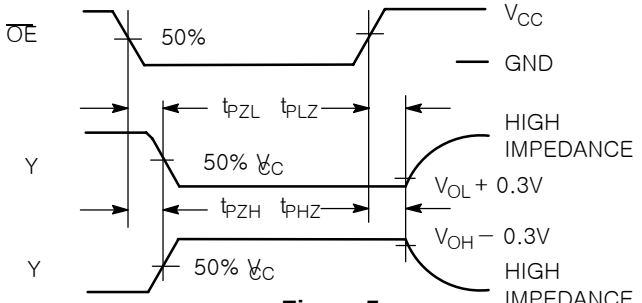
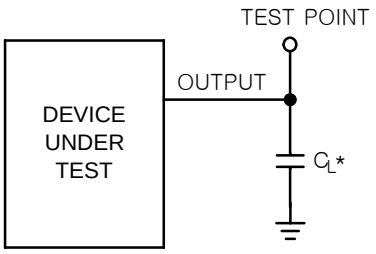
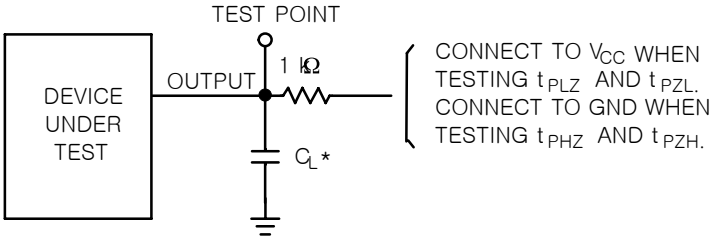


Figure 5.



*Includes all probe and jig capacitance

Figure 6. Test Circuit



*Includes all probe and jig capacitance

Figure 7. Test Circuit

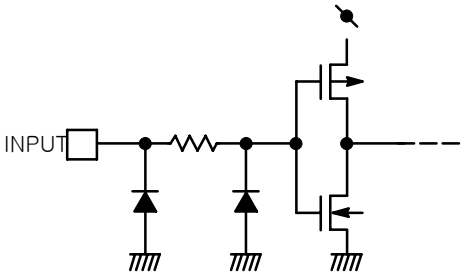
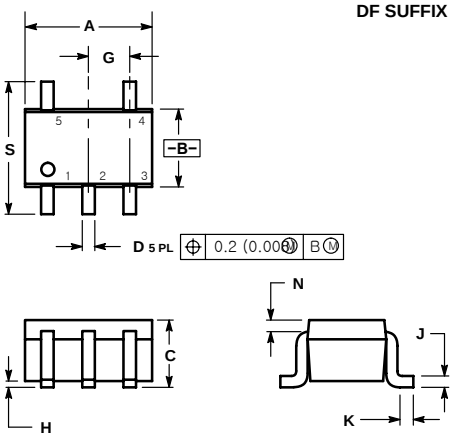


Figure 8. Input Equivalent Circuit

PACKAGE DIMENSIONS

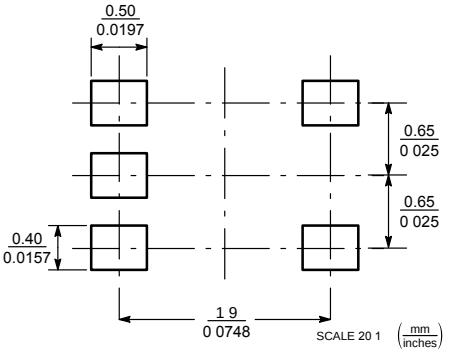
SC70−5/SC−88A/SOT−353
DF SUFFIX



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. 419A−01 OBSOLETE. NEW STANDARD 419A−02.
4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

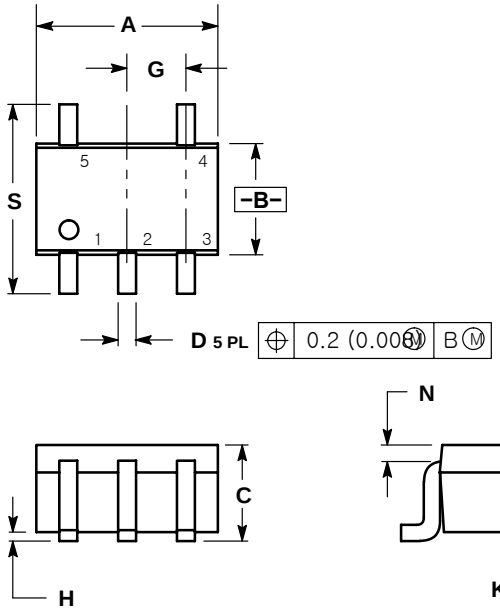
	NCHES		M LL METERS	
DIM	M N	MAX	M N	MAX
A	0 071	0 087	1 80	2 20
B	0 045	0 053	1 15	1 35
C	0 031	0 043	0 80	1 10
D	0.004	0.012	0.10	0.30
G	0.026 BSC		0.65 BSC	
H	−−−	0 004	−−−	0 10
J	0 004	0 010	0 10	0 25
K	0 004	0 012	0 10	0 30
N	0.008 REF		0.20 REF	
S	0.079	0.087	2.00	2.20

SOLDERING FOOTPRINT*



PACKAGE DIMENSIONS

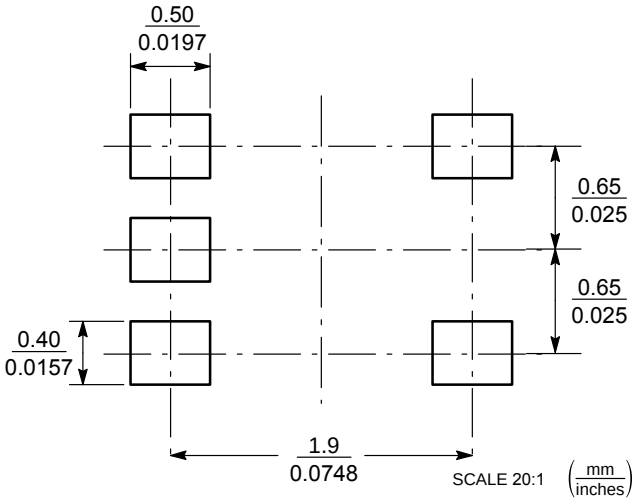
SC70−5/SC−88A/SOT−353
DF SUFFIX



NOTES:
1. D MENSION NG AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: NCH.
3. 419A−01 OBSOLETE. NEW STANDARD 419A−02.
4. D MENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

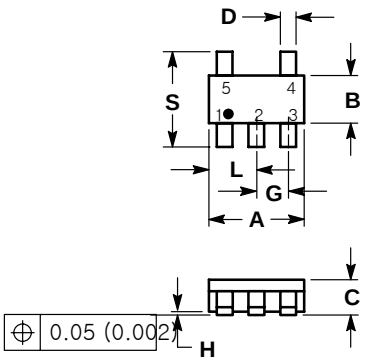
	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
A	0.071	0.087	1.80	2.20
B	0.045	0.053	1.15	1.35
C	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026 BSC		0.65 BSC	
H	−−−	0.004	−−−	0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20 REF	
S	0.079	0.087	2.00	2.20

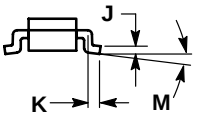
SOLDERING FOOTPRINT*



PACKAGE DIMENSIONS

SOT23−5/TSOP−5/SC59−5
DT SUFFIX





NOTES:
1. DIMENSION NG AND TOLERANCING PER ANSI Y14 5M, 1982.
2. CONTROLLING DIMENSION: M LLIMETER.
3. MAX MUM LEAD THICKNESS NCLUDES LEAD FINISH THICKNESS. M NIMUM LEAD THICKNESS IS THE MIN MUM THICKNESS OF BASE MATERIAL.
4. A AND B D MENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	2.90	3.10	0.1142	0.1220
B	1.30	1.70	0.0512	0.0669
C	0.90	1.10	0.0354	0.0433
D	0.25	0.50	0.0098	0.0197
G	0.85	1.05	0.0335	0.0413
H	0.013	0.100	0.0005	0.0040
J	0.10	0.26	0.0040	0.0102
K	0.20	0.60	0.0079	0.0236
L	1.25	1.55	0.0493	0.0610
M	0	10	0	10
S	2.50	3.00	0.0985	0.1181

SOLDERING FOOTPRINT*